Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Currently Amended) An optical film measuring device for measuring properties of a film of a measurement target at a predetermined film measurement position in an observation area, comprising:

a light source for emitting white light or multi-color light;

a light-projection optical system for projecting a light emitted from the light source to the observation area in the form of parallel light;

a photo-detector of a region-divided type in which a plurality of detection cells for receiving the light from the observation area are collected in a two-dimensional space;

an image-formation optical system for forming an image of light reflected by the measurement target in the observation area onto the photo-detector, said light being the light projected by the light-projection optical system;

a spectroscopic part that can make only light in a predetermined wavelength band incident upon the photo-detector and selectively switch the wavelength band; and

a signal processing portion for extracting a pattern registered beforehand from the image of the measurement target taken in by the photo-detector, defining a predetermined position in this pattern as the film measurement position, obtaining a plurality of images having different wavelengths selectively switched by the spectroscopic part with respect to the measurement target, and thereby measuring the properties of the film of the measurement target at a predetermined film measurement position based on the signals of the detection cells corresponding to the film measurement position of each of the plurality of images[[.]],

wherein the signal processing portion obtains images having different wavelengths selectively switched by the spectroscopic part with respect to the measurement target and

determines the film measurement position with the image in which a contrast of an image becomes highest among the plurality of images obtained.

2. (Cancelled)

3. (Cancelled)

4. (Previously Presented) The optical film measuring device according to claim 1, comprising:

a part for registering in a storage part as the registered pattern a pattern extracted on the basis of a characteristic point when the characteristic point is specified from an outside through an input part on an image of a measurement target taken in by the photo-detector; and

a part for displaying the extracted pattern in a condition where the pattern is superimposed on an image in the observation area.

5. (Previously Presented) The optical film measuring device according to claim 1, comprising:

a part for extracting a pattern contained in a partial image and registering it in a storage part as the registered pattern when the partial image is specified from an outside through an input part on an image of a measurement target taken in by the photo-detector; and

a part for displaying the extracted pattern in a condition where the pattern is superimposed on an image in the observation area.

6. (Previously Presented) The optical film measuring device according to claim 1, comprising:

a part for extracting as a pattern a region which has a roughly constant luminosity and contains one point or one region when the one point or one region is specified from an outside through an input part on an image of a measurement target taken in by the photo-detector; and

a part for displaying the extracted pattern in a condition where the pattern is superimposed on an image in the observation area.

7. (Cancelled)

8. (Currently Amended) ~~The optical film measuring device according to claim 1,~~ An optical film measuring device for measuring properties of a film of a measurement target at a predetermined film measurement position in an observation area, comprising:

a light source for emitting white light or multi-color light;

a light-projection optical system for projecting a light emitted from the light source to the observation area in the form of parallel light;

a photo-detector of a region-divided type in which a plurality of detection cells for receiving the light from the observation area are collected in a two-dimensional space;

an image-formation optical system for forming an image of light reflected by the measurement target in the observation area onto the photo-detector, said light being the light projected by the light-projection optical system;

a spectroscopic part that can make only light in a predetermined wavelength band incident upon the photo-detector and selectively switch the wavelength band; and

a signal processing portion for extracting a pattern registered beforehand from the image of the measurement target taken in by the photo-detector, defining a predetermined position in this pattern as the film measurement position, obtaining a plurality of images having different wavelengths selectively switched by the spectroscopic part with respect to the measurement target, and thereby measuring the properties of the film of the measurement target at a predetermined film measurement position based on the signals of the detection cells corresponding to the film measurement position of each of the plurality of images,

wherein the spectroscopic part is set so that a contrast of an image may be highest when the film measurement position determination part determines the film measurement position based on the image in the observation area.

9. (Currently Amended) ~~The optical film measuring device according to claim 1,~~ An optical film measuring device for measuring properties of a film of a measurement target at a predetermined film measurement position in an observation area, comprising:

a light source for emitting white light or multi-color light;

a light-projection optical system for projecting a light emitted from the light source to the observation area in the form of parallel light;

a photo-detector of a region-divided type in which a plurality of detection cells for receiving the light from the observation area are collected in a two-dimensional space;

an image-formation optical system for forming an image of light reflected by the measurement target in the observation area onto the photo-detector, said light being the light projected by the light-projection optical system;

a spectroscopic part that can make only light in a predetermined wavelength band incident upon the photo-detector and selectively switch the wavelength band; and

a signal processing portion for extracting a pattern registered beforehand from the image of the measurement target taken in by the photo-detector, defining a predetermined position in this pattern as the film measurement position, obtaining a plurality of images having different wavelengths selectively switched by the spectroscopic part with respect to the measurement target, and thereby measuring the properties of the film of the measurement target at a predetermined film measurement position based on the signals of the detection cells corresponding to the film measurement position of each of the plurality of images,

wherein based on information about a configuration of a measurement target, a wavelength band of a spectroscopic image in which a contrast of an image to be taken in by the photo-detector becomes highest is obtained by calculations from an optical constant and a thickness of the measurement target registered beforehand.

10. (Previously Presented) The optical film measuring device according to claim 1 , comprising a part for providing color display of each pixel in a color that corresponds to a

wavelength band having a highest detected light intensity in a visible light region of images that correspond to a plurality of obtained wavelength bands so that a film measurement position can be set on the color-displayed image.

11. (Previously Presented) The optical film measuring device according to claim 1, wherein in a case where an image of a measurement target to be taken in by the photo-detector is a periodic repetition of a pattern having a predetermined shape, the signal processing portion extracts a characteristic point of the pattern from the image of the measurement target taken in by the photo-detector and defines as the film measurement position a predetermined position with respect to the characteristic point.

12. (Original) The optical film measuring device according to claim 1, wherein in a case where an image of a measurement target to be taken in by the photo-detector has a frame-shaped pattern, a center of intersections of the patterns is defined as the film measurement point.

13. (Previously Presented) The optical film measuring device according to claim 1, wherein:

the signal processing portion determines a plurality of film measurement positions based on an image in the observation area taken in by the photo-detector: and

the signal processing portion obtains by operations properties of a film based on a signal extracted from the plurality of film measurement positions.

14. (Original) The optical film measuring device according to claim 1, wherein:

an image of a measurement target is taken in by the photo-detector in such a manner as to contain a corner of the measurement target; and

the corner of the measurement target is extracted from the image taken in by the photo-detector, to determine the film measurement position with respect to the corner of the measurement target thus extracted.

15. (Original) The optical film measuring device according to claim 1, wherein in a case where a plurality of measurement targets formed as divided on a substrate is to be measured:

an image of the measurement target is taken in by the photo-detector in such a manner as to contain a corner of the substrate; and

the corner of the substrate is extracted from the image taken in by the photo-detector, to determine the film measurement position of the measurement target with respect to the extracted substrate corner.

16. (Original) The optical film measuring device according to claim 15, wherein a region of the observation area where an image is taken in by the photo-detector can be set for each of product types.

17. (Previosly Presented) The optical film measuring device according to claim 1, wherein the spectroscopic part is equipped with spectroscopic filters for visible light to near-infrared light regions, and the device further comprising a part for measuring chromaticity and film thickness of a colored thin film.

18. (Previously Presented) The optical film measuring device according to claim 1, comprising a spectroscopic filter for a wavelength of about 450 nm, a spectroscopic filter for a wavelength of about 550 nm, a spectroscopic filter for a wavelength of about 650 nm, a plurality of spectroscopic filters for a visible light region, and a plurality of spectroscopic filters for near-infrared through infrared regions are arranged side by side, at least the spectroscopic filter for a wavelength of about 450 nm, spectroscopic filter for a wavelength of about 550 nm, and spectroscopic filter for a wavelength of about 650 nm being arranged consecutively in sequence.

19. (Original) The optical film measuring device according to claim 1, wherein reflected light and transmission light of light emitted from the light source with which a measurement target has been irradiated can be taken in by the photo-detector.